Got it!

Search XREF ?

ON Semiconductor®

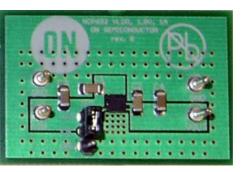
Energy Efficient Innovations

Products O Applications Tools O About O MyON

Home > Support > Design Support > Design Resources & Documents > Evaluation/Development Tools

NCP692MN18T2GEVB: 1.8 V CMOS LDO Evaluation Board

The NCP692 CMOS LDO family provides 1 A of output current with enhanced ESD in fixed output voltage options from 1.5 V to 5.0 V. These devices are designed for space constrained and portable battery powered applications and offer additional features such as low Dropout Voltage, high Power Supply Rejection Ratio (PSRR), low Quiescent and Ground Current consumption, low Noise operation, Short Circuit and Thermal Protection. NCP692 is designed to be used with low cost ceramic capacitors and the minimum value of 1 μ F output capacitance is required. The NCP692 device is equipped with Active High Enable pin, Active Output Discharge, Current Limit and Thermal Shutdown Protection. Finally the Surface Mount DFN3x3 package with Expose Pad allows saving PCB space and effectively dissipating heat through the PCB copper area. This demonstration board operates from a dc input voltage divider. External waveform generator could be connected to the EN (Enable) pin in order to verify the ON/OFF operation.



Previously Viewed Products
Select Product...

Design Support

- * Technical Documentation
- ** Design Resources &
- Documents >> Technical Support
- * Sales Support

Evaluation/Development Tool Information							
Product	Status	Compliance	Short Description		Parts Used	Action	
NCP692MN18T2GEVB	Active	Pb-free	1.8 V CMOS LDO Evaluation Board		NCP692MN18T2G	 Contact Local Sales Office Inventory 	
Technical Documents Type Document Title Document ID/Size Rev							
Eval Board: BOM	NCP692MN18T2GEVB Bill of Materials ROHS Compliant						0
Eval Board: Gerber	NCP692MI Format)	N18T2GEVB Gerbe	er Layout Files (Zip	NCP692MN18T2GEVB_GERBER.ZIP - 19.0 KB			0
Eval Board: Schematic	NCP692MI	N18T2GEVB Scher	natic	NCP692MN18T2GEVB_SCHEMATIC.PDF - 28.0 KB			0
Eval Board: Test Procedure	NCP692M	N18T2GEVB Test I	Procedure	NCP692MN18T2GEVB_TEST_PROCEDURE.PDF - 313.0 KB			0

Privacy Policy | Terms of Use | Site Map | Careers | Contact Us | Terms and Conditions | Mobile Portal | Mobile App

Copyright © 1999-2017 ON Semiconductor

Follow Us 👔 🛗 💆 🗗 😤